



<b>FORM PTO-1449</b>  <b>INFORMATION DISCLOSURE CITATION</b>				Attorney Docket: 1232-5220		Serial No.: 10/728,707	
				Applicant: TAKASE et al			
				Filing Date: December 4, 2003		Group Art Unit: 1645	
<b>U.S. PATENT DOCUMENTS</b>							
Examiner Initial		Patent Number	Issue Date	Name	Class	Sub-Class	Filing Date
HC	1	5,601,980	2/1997	Gordon et al	435		9/1994
HC	2	5,821,060	10/1998	Arlinghaus et al	435		8/1996
<b>FOREIGN PATENT DOCUMENTS</b>							
Examiner Initial		Patent Number	Publication Date	Country	Class	Sub-Class	Translation
HC	1	8210998	8/1996	Japan (see abstract)			<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
HC	2	2000516727	6/1998	Japan (see WO 9859362			<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
HC	3	98/59362	12/1998	WO			<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
HC	4	11-187900	7/1999	Japan (see abstract)			<input type="checkbox"/> Yes <input checked="" type="checkbox"/> No
<b>OTHER DOCUMENTS (Including Author, Title, Date, etc.)</b>							
HC	1	Schena et al; "Quantitative Monitoring of Genb Expression Patterns with a Complementary DNA Microarray", Science, Vol. 270, 20 October 1995; pp. 467-470.					
HC	2	Arlinghaus et al, "Analysis of Biosensor Chips for Identification of Nucleic Acids", Anal. Chem, Vol. 69, No. 18, Sept. 15, 1997, pp. 3747-3753					
HC	3	John et al, "Time-of-Flight Secondary Ion Mass Spectrometry Analysis of Biological Materials", Secondary Ion Mass Spectrometry SIMS VIII, Proceedings of the 8 <sup>th</sup> International Conference Amsterdam the Netherlands, Sept. 15-20, 1991, pp. 657-660; John Wiley & Sons					
HC	4	Lazzeri, et al, "Use of spin-coatd TXRF reference samples for ToF-SIMS metal contaminant quantification on silicon wafers; Surface and Interface Analysis 29, 20009, pp. 798-803					
HC	5	Search Report – PCT/JP03/08092, June 26, 2003					
Examiner /Heather Calamita/				Date Considered 08/30/2006			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP §609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							